Abstracts

Repeat measurements and metrics for nonlinear model development

K.A. Remley, J.A. Jargon, D. Schreurs, D.C. DeGroot and K.C. Gupta. "Repeat measurements and metrics for nonlinear model development." 2002 MTT-S International Microwave Symposium Digest 02.3 (2002 Vol. III [MWSYM]): 2169-2172 vol.3.

We develop a method to study nonlinear models using metrics in conjunction with repeat measurements. We illustrate this procedure by investigating the performance of three types of measurement-based nonlinear circuit models using two different metrics.

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